

Notice of References Cited	Application/Control No. 10/774,100	Applicant(s)/Patent Under Reexamination QING ET AL.	
	Examiner Hong Cho	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,266,694 B1	07-2001	Duguay et al.	709/223
*	B	US-2001/0036164 A1	11-2001	Kakemizu et al.	370/331
*	C	US-2002/0071389 A1	06-2002	Seo, Hyun-Chul	370/232
*	D	US-6,594,268 B1	07-2003	Aukia et al.	370/400
*	E	US-6,760,306 B1	07-2004	Pan et al.	370/230
*	F	US-2004/0165597 A1	08-2004	Bicknell et al.	370/395.31
*	G	US-2005/0018605 A1	01-2005	Foote et al.	370/230
*	H	US-6,967,954 B2	11-2005	Sugiyama, Kazuhiko	370/395.52
*	I	US-7,082,102 B1	07-2006	Wright, Steven A.	370/229
*	J	US-7,092,380 B1	08-2006	Chen et al.	370/352
*	K	US-7,120,151 B1	10-2006	Ginjpalli et al.	370/395.1
*	L	US-7,161,946 B1	01-2007	Jha, Pankaj K.	370/401
*	M	US-7,215,640 B2	05-2007	Matsubara, Daisuke	370/235

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.